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PATENTS

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of

Hirotaka NAKANO et al.

Confirmation No. 9420

Serial No. 09/855,723

Group 2812

Filed May 16, 2001

**RECEIVED**

OCT 21 2003

SYSTEM OF MANUFACTURING SEMICONDUCTOR  
INTEGRATED CIRCUIT

**Technology Center 2600**

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Sir:

In compliance with Rules 1.97 and 1.98, and in fulfillment of the duty of disclosure under Rule 1.56, the accompanying documents, copies of which are attached to this statement, are made of record on the enclosed Form PTO-1449.

A concise explanation of the relevance of these items is that these references were cited by the Korean Patent Office in a Korean Official Action. A copy of the Korean Official Action in which they were cited is attached hereto as well as a Japanese translation of the Korean Official Action. An English translation of the pertinent portion enclosed in a wavy line is also attached hereto.

Under the provisions of 37 CFR 1.97(e), the undersigned hereby certifies that each item of information contained in this Supplemental Information Disclosure Statement was first cited in any communication from a foreign Patent

Office in a counterpart foreign application not more than three months prior to the filing of this Statement.

Respectfully submitted,

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By



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October 17, 2003

NAKANO et al.-U.S. Pat. Appl. 09/855,723  
Ref. WN-2338

The invention relating to Claim 1 of the Scope of Patent Claims of the present application could easily have been invented prior to the present application by a person of ordinary skill in the field of technology pertaining to the invention. Therefore, in accordance with Patent Law Article 29 Section 2, a patent may not be granted.

Postscript

1. Citation invention 1:

Korean Laid Open Patent Publication  
(Patent 2000-0024317; Laid Open 05/06/2000)

2. Citation invention 2:

Japanese Laid Open Patent Publication  
(Hei 11-224284; Laid Open 08/17/1999)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

\* Abstract provided for the Examiner's convenience